Supplementary Figures



Figure S1 Randles equivalent circuit used to characterise E-MIPs, comprising a charge transfer resistance (R_{CT}) between the solution and the electrode surface, solution resistance (R_s), the Warburg impedance (Z_w), associated with the diffusion of the electroactive species from the solution towards the electrode surface), and the double layer capacitance (C_{dl}).





Figure S2a BHb determination using NIP-modified BT-Au electrode (giving imprinting factor, IF = 146:1 at 1 nM); Figure S2b BSA determination using BHb MIP-modified BT-Au electrode (giving selectivity factor, α = 6 at 1 nM). Data represents mean ± S.E.M., n = 3.

Sample	Number of	Average Roughness	RMS Roughness
	measurements	R _a / nm	R _q / nm
AT-Au	4	388 ±105	499 ±127
AT-Au NIP	2	399 ±6	542 ±4
AT-Au MIP	4	327 ±49	439 ±87
BT-Au	4	504 ±45	636 ±52
BT-Au NIP	1	489	623
BT-Au MIP	3	533 ±82	672 ±106

Table S1 Roughness data obtained for AT-Au and BT-Au electrodes, both before and after coating with polymers. Uncertainties are calculated from the standard deviations of the measurements.